

Title (en)
WELL PLATE FOR XRF MEASUREMENTS

Title (de)
WANNENPLATTE FÜR RÖNTGENFLUORESZENZ MESSUNGEN

Title (fr)
PLAQUE DE PUIITS POUR DES MESURES À XRF

Publication
EP 2183644 A1 20100512 (EN)

Application
EP 08798006 A 20080815

Priority
• US 2008073359 W 20080815
• US 96505207 P 20070816

Abstract (en)
[origin: WO2009023847A1] The present invention includes an apparatus for preparing samples for measurement by x-ray fluorescence spectrometry. The apparatus comprises a plate having one or more through holes which are less than 500 micrometers across in one dimension where a film covers the holes on one side of the plate. The film is translucent to x-rays. In another embodiment, the holes are covered on one side of the plate by a detachable cover forming a water-tight seal against the plate. The cover is substantially free of the elements osmium, yttrium, indium, phosphorus, zirconium, platinum, gold, niobium, mercury, thallium, molybdenum, sulfur, lead, bismuth, technetium, ruthenium, chlorine, rhodium, palladium, argon, silver, and thorium. The present invention also comprises providing a solution of less than 10 micromolar and a volume between about 2 microliters and about 2 milliliters. The solution is concentrated and analyzed using x-ray fluorescence spectrometry.

IPC 8 full level
G01N 23/22 (2006.01); **G01N 23/223** (2006.01); **G03B 42/02** (2006.01)

CPC (source: EP US)
G01N 23/2202 (2013.01 - US); **G01N 23/2204** (2013.01 - EP US); **G01N 23/223** (2013.01 - US); **G03B 42/02** (2013.01 - EP US); **G01N 2223/074** (2013.01 - US); **G01N 2223/076** (2013.01 - EP US); **G01N 2223/309** (2013.01 - US); **G01N 2223/64** (2013.01 - US)

Designated contracting state (EPC)
AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MT NL NO PL PT RO SE SI SK TR

Designated extension state (EPC)
AL BA MK RS

DOCDB simple family (publication)
WO 2009023847 A1 20090219; DK 2183644 T3 20160829; EP 2183644 A1 20100512; EP 2183644 A4 20120118; EP 2183644 B1 20160608; ES 2585345 T3 20161005; JP 2010537171 A 20101202; JP 2013224946 A 20131031; JP 2015004692 A 20150108; JP 5628035 B2 20141119; JP 5755682 B2 20150729; JP 6076308 B2 20170208; US 10782253 B2 20200922; US 2009046832 A1 20090219; US 2013034205 A1 20130207; US 2015023467 A1 20150122; US 2017010228 A1 20170112; US 8238515 B2 20120807; US 8873707 B2 20141028; US 9476846 B2 20161025

DOCDB simple family (application)
US 2008073359 W 20080815; DK 08798006 T 20080815; EP 08798006 A 20080815; ES 08798006 T 20080815; JP 2010521206 A 20080815; JP 2013117600 A 20130604; JP 2014202871 A 20141001; US 19276208 A 20080815; US 201213567613 A 20120806; US 201414508322 A 20141007; US 201615273767 A 20160923